Product data sheet

1. General description

WeEnPACK-B2 module with WeEn 1200V Gen2 SiC MOSFET and Pressfit type. Integrated with NTC temperature sensor.



2. Features and benefits

- · Half bridge topology
- Press-fit pin configuration
- Low R_{DSon}-T_j coefficient
- Low Switching Losses
- Low Q_a and C_{rss}
- Mimimized circuit impedance
- Improved chip synchronization performance

3. Applications

- · Power inverters
- AC-DC converters
- · DC-DC converters
- · Active power factor correctors
- Motor drivers

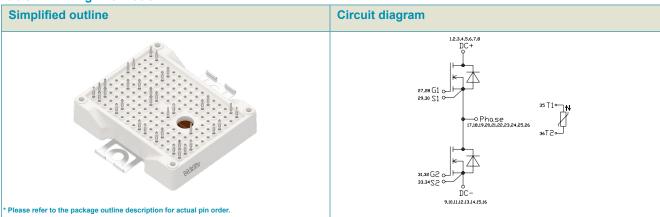
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes		Values		Unit
Absolute	maximum rating						
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C			227		Α
P _{tot}	total power dissipation	T _h = 25 °C			272		W
T _j	junction temperature			-40 to 150			°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	aracteristics						
$R_{\text{DS(on)}}$	drain-source on-state resistance	V _{GS} = 15 V; I _D = 250 A; T _j = 25 °C		-	4.0	-	mΩ
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 250 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = 0 \text{ V}/18 \text{ V};$		-	945	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	191	-	nC
Source-d	rain diode						
Q _r	recovered charge	I_{SD} = 250 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt =2800 A/ μ s;		-	1482	-	nC

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	•	Package issue date
WMSC004H12B2P	WeEnPACK-B2	WMSC004H12B2P6T	Tray	12	WeEnPACK- B2PHB-B	19-Apr-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC004H12B2P	WMSC004H12B2P

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T_{stg}	storage temperature			-40 to 150	°C
$T_{j.op}$	operating junction temperature			-40 to 150	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET					
V _{DS}	drain-source voltage	T _j = 25 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{\rm GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		272	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		227	А
		V _{GS} = 18 V; T _h = 100 °C		144	Α
I _{DM}	peak drain current	pulsed; tp \leq 10 us; T _h = 25 °C		454	Α
E _{as}	single pulse drain-to- source avalanche	$I_{AS} = 30 \text{ A}; L = 1 \text{ mH}; V_{DD} = 100 \text{ V};$ $T_{j(\text{init})} = 25 ^{\circ}\text{C}; \text{ each die}$		450	mJ
Body Diod	е				
I _{SD}	DC body diode forward current	$T_h = 25 ^{\circ}C; V_{GS} = -4 V$		75	А
I _{SD,pulse}	Pulse body diode current	verified by design, tp limited by T_{jmax}		454	Α

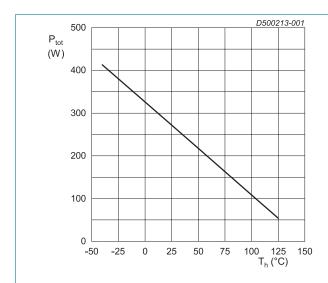


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

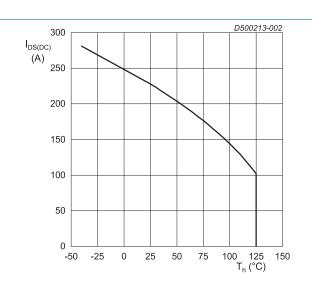


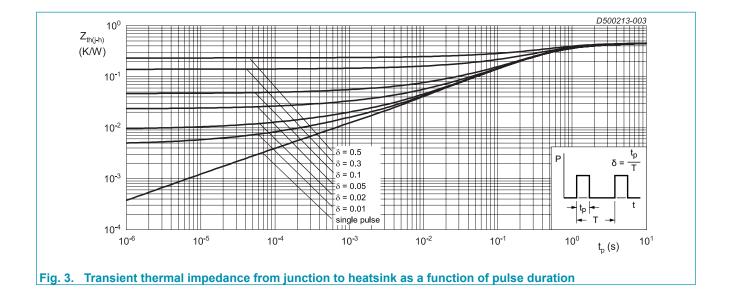
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.1	-	K/W
R _{th(j-h)}	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 3 \text{ W/(m·K)}$, thick _{grease} = 50 um		-	0.46	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al2O3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
СТІ	Comperative tracking index				>200	,	
F	Mounting force per clamp			40	-	80	N
G	Approximate Weight			-	36	-	g

Note: Module is ESD sensitive. Handling precautions are recommanded.

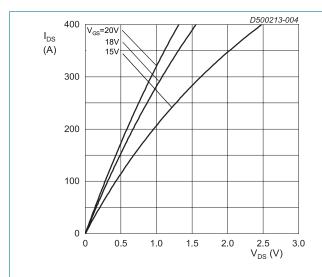


10. Characteristics

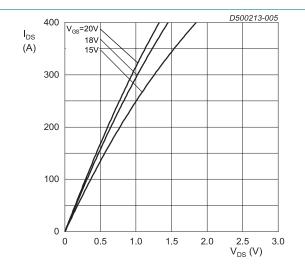
Table 7. Characteristics

MOSFET							
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 500 \mu A; V_{GS} = 0 V; T_j = 25 °C$		1200	-	-	V
$V_{\text{GS(th)}}$	gate-source threshold voltage	$I_D = 100 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$		1.9	2.5	3.5	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	1	500	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	50	500	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	50	500	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 250 A; T _j = 25 °C		-	4.0	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 250 A; T _j = 25 °C		-	3.2	6.0	mΩ
		V _{GS} = 18 V; I _D = 250 A; T _j = 125 °C		-	4.7	-	mΩ
		V _{GS} = 18 V; I _D = 250 A; T _j = 150 °C		-	5.2	-	mΩ
$R_{\scriptscriptstyle G}$	gate resistance	$f = 1 \text{ MHz}$; $T_j = 25 \text{ °C}$; each die with 4.7Ω $R_{G\text{-ext}}$ in series		-	1.08	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 250 A; T _j = 25 °C		-	84	-	S
Dynamic	characteristics						1
Q _{G(tot)}	total gate charge	I _D = 250 A; V _{DS} = 800 V; V _{GS} = 0 V/18 V;		-	945	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C		-	280	-	nC
Q_{GD}	gate-drain charge			-	191	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 1 MHz;		-	23	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	1003	-	pF
C _{rss}	reverse transfer capacitance			-	74	-	pF
E _{oss}	Coss stored energy			-	502	-	μJ
t _{d(on)}	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	75	-	ns
t _r	rise time	$R_{G(ext)}$ = 3.0 Ω; I_D = 250 A; L = 100 μH; T_i = 25 °C		-	109	-	ns
$t_{\text{d(off)}}$	turn-off delay time	1 ,		-	180	-	ns
t _f	fall time			-	42	-	ns
E _{on}	turn-on energy			-	12.1	-	mJ
E _{off}	turn-off energy	1		-	5.5	-	mJ

Body dic	de						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,				
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_{SD} = 250 \text{ A}; T_j = 25 \text{ °C}$		-	5.8	-	V
		$V_{GS} = -4 \text{ V}; I_{SD} = 250 \text{ A}; T_j = 150 \text{ °C}$		-	5.2	-	V
Dynamic	characteristics		'		'	'	
I _{rrm}	reverse recovery current	$I_{SD} = 250 \text{ A}; V_{GS} = -4 \text{ V}/18 \text{ V}; V_{R} = 600 \text{ V};$		-	75	-	Α
t _{rr}	reverse recovery time	di/dt = 2800 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	35	-	ns
Q _r	recovered charge	J		-	1482	-	nC
E _{rec}	reverse recovery energy			-	107	-	μJ
NTC ther	mistor						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C			493±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	s

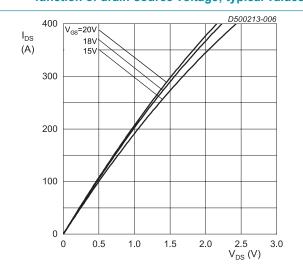


T_j = -40 °C; t_p < 200 μs Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

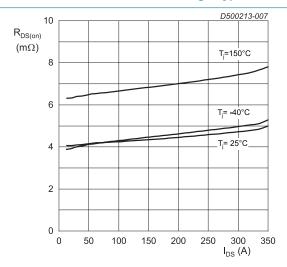


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

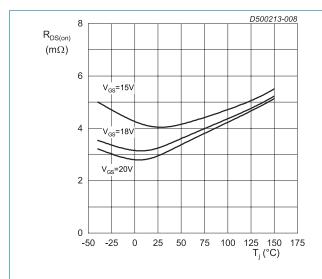
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



 T_j = 150 °C; t_p < 200 µs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

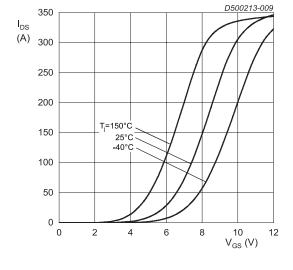


 V_{GS} = 18 V; t_p < 200 µs Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



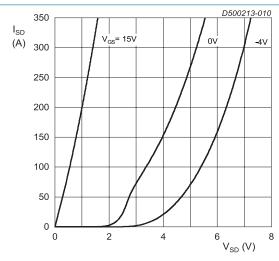
 $I_{DS} = 250 \text{ A}; t_p < 200 \text{ }\mu\text{s}$

Fig. 8. Drain-source on-state resistance as a function of junction temperature



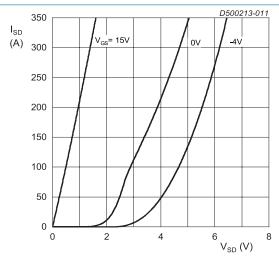
 $V_{DS} = 50 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



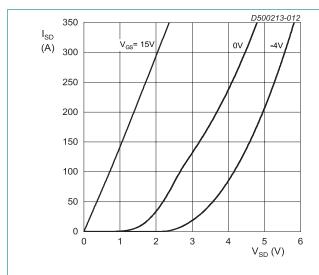
 $T_{j} = -40 \, ^{\circ}\text{C}; \, t_{p} < 200 \, \mu\text{s}$

Fig. 10. Body diode forward characteristics; typical values

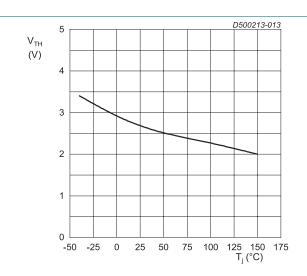


 $T_j = 25 \, ^{\circ}C; t_p < 200 \, \mu s$

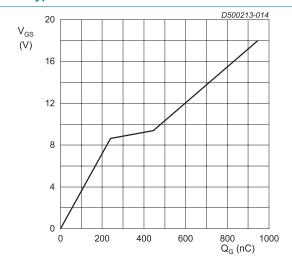
Fig. 11. Body diode forward characteristics; typical values



T_j = 150 °C; t_p < 200 μs Fig. 12. Body diode forward characteristics; typical values



V_{DS} = 10 V; I_{DS} = 100 mA Fig. 13. Threshold voltage as a function of junction temperature



 I_{DS} = 250 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

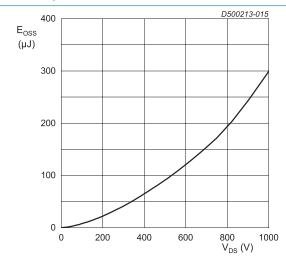
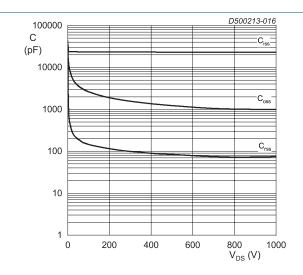
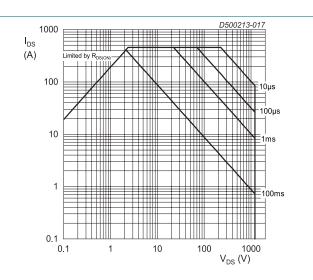


Fig. 15. Output capacitor stored energy as a function of drain-source voltage

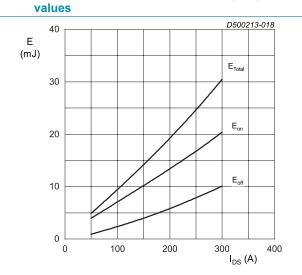


 $V_{DS} = 0 - 1000 V$ $T_i = 25 \, ^{\circ}\text{C}; \, V_{AC} = 25 \, \text{mV}; \, f = 1 \, \text{MHz}$ Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical



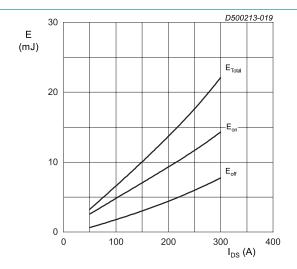
 $T_i = 25 \,^{\circ}C; D = 0$ Parameter: t_p

Fig. 17. Forward bias safe operating area



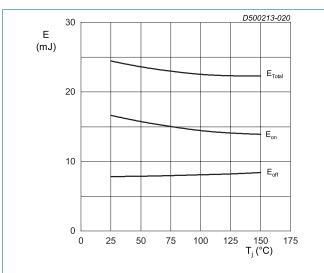
 T_{j} = 25 °C; V_{DD} = 800 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



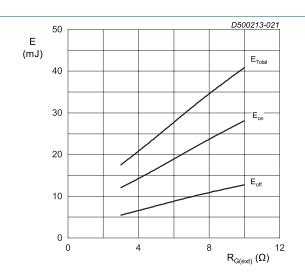
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 3 $\Omega;$ $R_{G(on)}$ = 3 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



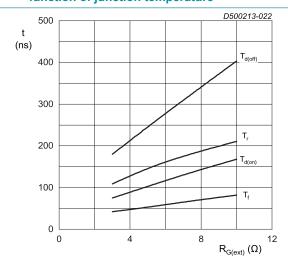
 I_{DS} = 250 A; V_{DD} = 800 V; $R_{G(off)}$ = 5.1 $\Omega;$ $R_{G(on)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



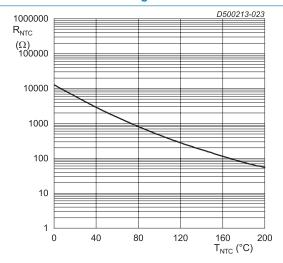
 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 250 A; $V_{\rm GS}$ = -4 V/18 V; $L = 100 \mu H$

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



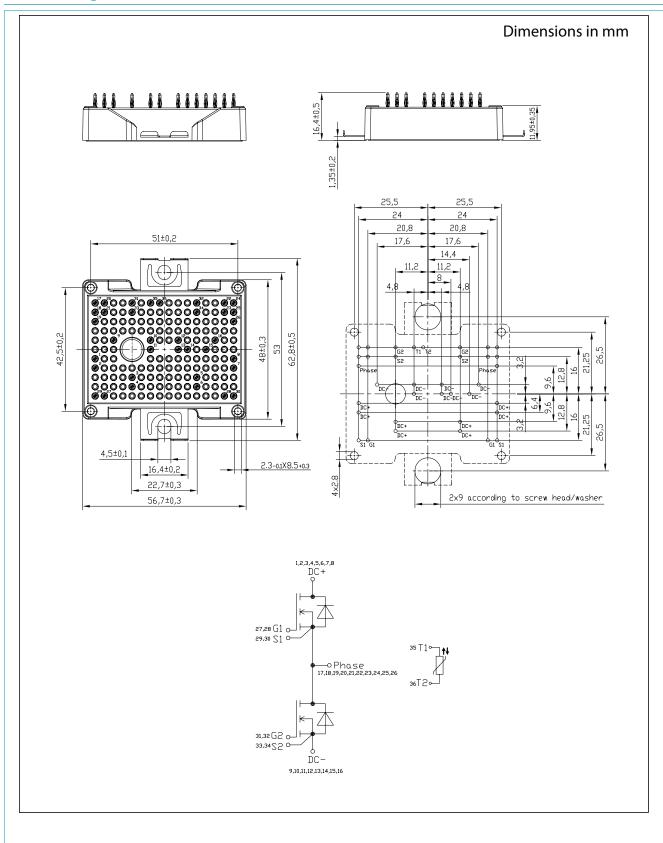
 $T_i = 25$ °C; $V_{DD} = 800$ V; $I_{DS} = 250$ A; $V_{GS} = -4$ V/18 V; Fig. 23. NTC thermistor resistance as a function of $L = 100 \mu H$

Fig. 22. Switching time as a function of external gate resistance



NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions".
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WMSC004H12B2P

N-Channel Silicon Carbide MOSFET Module

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